

Application/Control	No.
10/671 768	

Examiner

Mark Eashoo, Ph.D.

Applicant(s)/Patent under Reexamination
DANEKAS ET AL.

Art Unit 1732

				ISSUE	CL	.AS	SIF	ICAT	ION				
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n/a (Assistant Examiner) (Date)					K EASHOO, PH.D MARY EXAMINER				Total Claims Allowed: 10				
(Legal In		(Primary Examiner) (Date)					O.G. Print Claim(s)						

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